

# Amir Avishai

## List of Publications by Year in descending order

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28  
papers

541  
citations

840776

11  
h-index

713466

21  
g-index

28  
all docs

28  
docs citations

28  
times ranked

790  
citing authors

#	ARTICLE	IF	CITATIONS
1	Myelination and Axonal Electrical Activity Modulate the Distribution and Motility of Mitochondria at CNS Nodes of Ranvier. <i>Journal of Neuroscience</i> , 2011, 31, 7249-7258.	3.6	158
2	Enhanced fatigue resistance in 316L austenitic stainless steel due to low-temperature paraequilibrium carburization. <i>Acta Materialia</i> , 2007, 55, 5572-5580.	7.9	75
3	Intergranular films at metal-ceramic interfaces Part I - interface structure and chemistry. <i>Acta Materialia</i> , 2005, 53, 1559-1569.	7.9	60
4	Lunar periodicity of planula release in the reef-building coral <i>Stylophora pistillata</i> . <i>Marine Ecology - Progress Series</i> , 2006, 311, 93-102.	1.9	41
5	Solubility Limit of MgO in Al <sub>2</sub> O <sub>3</sub> at 1600°C. <i>Journal of the American Ceramic Society</i> , 2006, 89, 350-353.	3.8	38
6	Use of an Underlayer for Large Area Crystallization of Rubrene Thin Films. <i>Chemistry of Materials</i> , 2017, 29, 6666-6673.	6.7	34
7	Intergranular films at metal-ceramic interfaces Part II - calculation of Hamaker coefficients. <i>Acta Materialia</i> , 2005, 53, 1571-1581.	7.9	28
8	Amorphous Films at Metal/Ceramic Interfaces. <i>International Journal of Materials Research</i> , 2003, 94, 272-276.	0.8	22
9	Local Measurement of Janus Particle Cap Thickness. <i>ACS Applied Materials &amp; Interfaces</i> , 2018, 10, 30925-30929.	8.0	18
10	Intergranular films in metal-ceramic composites and the promotion of metal particle occlusion. <i>International Journal of Materials Research</i> , 2004, 95, 266-270.	0.8	17
11	Serial sectioning for examination of photoreceptor cell architecture by focused ion beam technology. <i>Journal of Neuroscience Methods</i> , 2011, 198, 70-76.	2.5	13
12	Transmission Kikuchi Diffraction study of texture and orientation development in nanostructured hard turning layers. <i>CIRP Annals - Manufacturing Technology</i> , 2015, 64, 73-76.	3.6	11
13	Methods for Conducting Electron Backscattered Diffraction (EBSD) on Polycrystalline Organic Molecular Thin Films. <i>Microscopy and Microanalysis</i> , 2018, 24, 420-423.	0.4	6
14	Three-Dimensional Analysis of Optic Nerve Axons Using a Focused Ion Beam-Based Approach. <i>Microscopy Today</i> , 2010, 18, 18-22.	0.3	5
15	Chemical bath deposition of CdS highly-textured, columnar films. <i>Thin Solid Films</i> , 2011, 519, 6388-6393.	1.8	3
16	Characterization of Dental Bonded Interface Degradation Using Focused Ion Beam and High-Resolution Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2009, 15, 368-369.	0.4	2
17	Focused Ion-Beam (FIB) Nanomachining of Silicon Carbide (SiC) Stencil Masks for Nanoscale Patterning. <i>Materials Science Forum</i> , 0, 717-720, 889-892.	0.3	2
18	Transmission Electron Diffraction Investigation of White Etching Areas in Bearing Steels: A Comparison Between TKD and TEM. <i>Microscopy and Microanalysis</i> , 2014, 20, 1476-1477.	0.4	2

#	ARTICLE	IF	CITATIONS
19	Tackling Characterization Challenges in High Deformation/Stress Steel Alloys Using Transmission Kikuchi Diffraction (TKD). <i>Microscopy and Microanalysis</i> , 2015, 21, 2377-2378.	0.4	2
20	Focused Ion Beam-based Three Dimensional Analysis of Optic Nerve Axons. <i>Microscopy and Microanalysis</i> , 2009, 15, 346-347.	0.4	1
21	Three-Dimensional Characterization of Dental Bonded Interface Degradation Using Serial Ion-Ablation Scanning Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2011, 17, 1016-1017.	0.4	1
22	Orientation Mapping by Precession Transmission Electron Microscopy. <i>Microscopy and Microanalysis</i> , 2015, 21, 1661-1662.	0.4	1
23	FIB Overview. , 2019, , 335-350.		1
24	Equilibrium Amorphous Films at Metal-Ceramic Interfaces. <i>Microscopy and Microanalysis</i> , 2004, 10, 274-275.	0.4	0
25	FIB and HRTEM Characterization of Surface Oxides on Polysilicon MEMS after Cyclic Loading. <i>Microscopy and Microanalysis</i> , 2008, 14, 1010-1011.	0.4	0
26	What is the Effective Geometrical Collection Efficiency of Your XEDS Detector? A Routine Procedure Applied in a SEM Laboratory.. <i>Microscopy and Microanalysis</i> , 2016, 22, 412-413.	0.4	0
27	Microanalysis of Geologic Materials Exposed to Surface Conditions on the Planet Venus. <i>Microscopy and Microanalysis</i> , 2017, 23, 2188-2189.	0.4	0
28	Promoting Undergraduate Student Experiential Learning, using Advanced Microscopy and Spectroscopy Instrumentation on Common Materials. <i>Microscopy and Microanalysis</i> , 2018, 24, 2352-2353.	0.4	0